

## **THE DEVELOPMENT OF TWO COLOR MULTI LAYER MIRROR SYSTEM AND IT'S APPLICATION FOR MICRO BEAM X-RAY DIFFRACTOMETRY**

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The multi layer optics technology is well know as a tool to make monochromatic micro beam X-ray beam for XRD. We have developped the new optics which works both Cu and Cr $\alpha$  radiation just changing anode material. This optics is combined with micro focus rotating anode X-ray generator and the cylindrical Imaging Plate detector. It provides more then 100x flux compare with conventional seald tube pin hole camera systems at 10 micron measurement area.

We will introduce the mechanizm of two color multi layer optics and micro beam XRD applications such as very small area pole figure, qualitative analysis and 10micron single crystal structure analysis.